Sheet 1 of 2 Substitute Form PTO-1449 (Modified) J.S. Department of Commerce Patent and rademark Office Attorney's Docket No. Application No. 05770-095001 09/616,810 Information Disclosure Statement Applicant LESLIE G. FRITZEMEIER ET AL. by Applicant (Use several sheets if necessary) Filing Date Group Art Unit

July 14, 2000

(37 CFR §1.98(b)) **U.S. Patent Documents** Examiner Desig. Patent Filing Date Initial Number ID Issue Date Patentee Class Subclass If Appropriate Gom AA 6,027,564 02/22/2000 Fritzemeier et al. AB AC AD AE ΑF AG AH ΑI ΑJ AK

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